Application/Control No. Applicant(s)/Patent Under Reexamination 10/710,678 SUN ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 3748 Thai-Ba Trieu **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY US-Α US-В US-С US-D US-Ε US-F US-G US-Н US-US-J US-K US-L US-**FOREIGN PATENT DOCUMENTS Document Number** Date Country Classification Name Country Code-Number-Kind Code MM-YYYY CN 1737346 A 02-2006 CUI et al. F02B 37/00 China Ν 0 Р Q R S T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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